

Search Notes

Application/Control No.

10/801,870

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

VELEZ ET AL.

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	104.05	↓	↓
15	104.33	9/13/2005	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, OCR, DERWENT, EPO, JPO	↓	↓
Inventor name search	9/13/2005	RC